

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. 10/232,794
Priority Filing Date August 28, 2002
Inventor Luan Tran et al.
Assignee Micron Technology, Inc.
Priority Group Art Unit 2814
Priority Examiner H. Weiss
Attorney's Docket No. MI22-2555
Title: A Method of Forming Integrated Circuitry (As amended)

INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

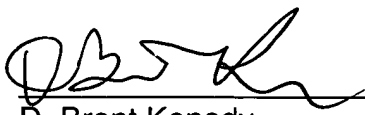
In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending application Serial No. 10/232,794, filed August 28, 2002, upon which the above-identified application relies for a priority date under 35 U.S.C. §120. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. §1.98(d) and MPEP §609(2). As a courtesy, copies of foreign and articles are enclosed.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: 4-21-04



D. Brent Kenady
Reg. No. 40,045

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2555	SERIAL NO. Filed Herewith		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Luan Tran et al.			
				FILING DATE Filed Herewith	GROUP		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,045,899	09/03/91	Arimoto			
	AB	5,107,459	04/21/92	Chu et al.			
	AC	5,350,706	09/27/94	McElroy et al.			
	AD	5,469,383	11/21/95	McElroy et al.			
	AE	5,537,347	07/16/96	Shiratake et al.			
	AF	5,508,541	04/16/96	Hieda et al.			
	AG	5,383,151	01/17/95	Onishi et al.			
	AH	5,726,092	03/10/98	Mathews et al.			
	AI	5,595,928	01/21/97	Lu et al.			
	AJ	5,747,844	05/05/98	Aoki et al.			
	AK	5,665,623	09/09/97	Liang et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AL	JP 03205868	09/09/91	Japan			Abs.
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR		A. Chatterjee et al., "A Shallow Trench Isolation Study for 0.25/0.18 μ m CMOS Technologies and Beyond",				
			IEEE, 1996 Symposium on VLSI Technology Digest of Technical Papers, pp. 156-57 (1996).				
	AS		M. Aoki et al., "Fully Self-Aligned 6F ² Cell Technology for Low Cost 1Gb DRAM", IEEE				
			1996 Symposium on VLSI Technology Digest of Technical Papers, pp. 22-23 (1996).				
	AT		J.S. KIM et al., "A Triple Level Metallization Technique for Gigabit Scaled DRAMS", VMIC CONFERENCE, Technology				
			Development, Memory Device Business, Samsung Electronic Co., pp. 28-33 (June 18-20, 1996).				
EXAMINER				DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	5,637,528	Higashitani et al.				
	AB	5,756,390	Juengling et al.				
	AC	5,736,670	Carbonell et al.				
	AD						
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	AJ						
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	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AR		B. KEETH, "A Novel Architecture for Advanced High Density Dynamic Random Access Memories".
			A Thesis for M.S. E.E., University of Idaho pp. 1-62 (i-vi); (May 1996).
	AS		T. Hamamoto et al., "NAND-Structured Trench Capacitor Cell Technologies for 256 Mb DRAM and Beyond",
			IEICE Transactions On Electronics, pp. 789-796, 1995.
	AT		M. Noguchi et al., "0.29- μm^2 Trench Cell Technologies for 1G-bit DRAMs with Open/Folded-Bit-Line Layout and Selective Growth Technique",
			1995 Symposium on VLSI Technology Digest of Technical Papers, pp. 137-138.

EXAMINER	DATE CONSIDERED
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							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR		V. Mathews et al., <i>Dry O₂ High Pressure Field Oxidation for 0.25 μm Isolation Technology</i> .				
			SSDM '95 - Device and Process Technology, 2 pages.				
	AS		Fazen, et al., "A High-C Capacitor (20.4fF/ μ ²) with Ultrathin CVD-Ta ₂ O ₅ films Deposited on Rugged Poly-Si for High Density DRAMs"; 1992; 4 pps.				
	AT		Fazen et al., "A Highly Manufacturable Trench Isolation Process for Deep Submicron DRAMS," ©1993 IEEE, 4 pages.				
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